ECOSPARK®2 300 mJ, 400 V, N-Channel Ignition IGBT

FGB3040G2-F085, FGD3040G2-F085, FGP3040G2-F085, FGI3040G2-F085

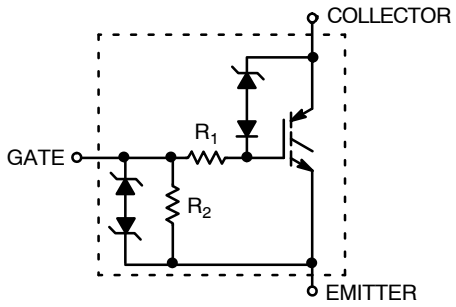
Features

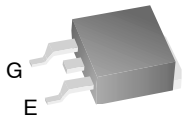
- SCIS Energy = 300 mJ at T_J = 25°C
- Logic Level Gate Drive
- AEC−Q101 Qualified and PPAP Capable
- These Devices are Pb−Free and are RoHS Compliant

Applications

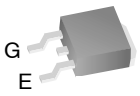
- Automotive Ignition Coil Driver Circuits
- Coil On Plug Applications

SYMBOL

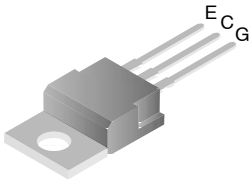




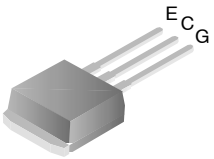
JEDEC TO−263AB
D²PAK−3 (TO−263, 3−LEAD)
CASE 418AJ



JEDEC TO−263AA
DPAK3 (TO−252 3 LD)
CASE 369AS

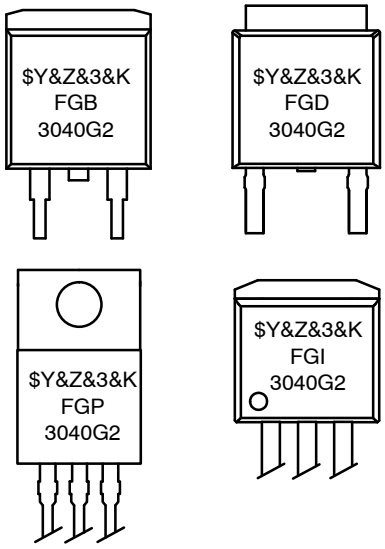


JEDEC TO−220AB
TO−220−3LD
CASE 340AT



JEDEC TO−262AA
I2PAK (TO−262 3 LD)
CASE 418AV

MARKING DIAGRAMS



FGx3040G2	= Specific Device Code (x = B/D/P/I)
$Y	= **onsemi** Logo
&Z	= Assembly Plant Code
&3	= 3−Digit Date Code
&K	= 2−Digits Lot Run Traceability Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 8 of this data sheet.

DEVICE MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Rating	Unit
BV_{CER}	Collector to Emitter Breakdown Voltage (I_C = 1 mA)	400	V
BV_{ECS}	Emitter to Collector Voltage − Reverse Battery Condition (I_C = 10 mA)	28	V
E_{SCIS25}	Self Clamping Inductive Switching Energy (Note 1)	300	mJ
$E_{SCIS150}$	Self Clamping Inductive Switching Energy (Note 2)	170	mJ
I_{C25}	Collector Current Continuous, at V_{GE} = 5.0 V, T_C = 25°C	41	A
I_{C110}	Collector Current Continuous, at V_{GE} = 5.0 V, T_C = 110°C	25.6	A
V_{GEM}	Gate to Emitter Voltage Continuous	±10	V
P_D	Power Dissipation Total, at T_C = 25°C	150	W
	Power Dissipation Derating, for T_C > 25°C	1	W/°C
T_J	Operating Junction Temperature Range	−55 to +175	°C
T_{STG}	Storage Junction Temperature Range	−55 to +175	°C
T_L	Max. Lead Temp. for Soldering (Leads at 1.6 mm from case for 10 s)	300	°C
T_{PKG}	Reflow Soldering according to JESD020C	260	°C
ESD	HBM−Electrostatic Discharge Voltage at 100 pF, 1500 Ω	4	kV
	CDM−Electrostatic Discharge Voltage at 1 Ω	2	kV

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Self Clamping Inductive Switching Energy (E_{SCIS25}) of 300 mJ is based on the test conditions that starting Tj = 25°C; L = 3 mHy, I_{SCIS} = 14.2 A, V_{CC} = 100 V during inductor charging and V_{CC} = 0 V during the time in clamp.
2. Self Clamping Inductive Switching Energy ($E_{SCIS150}$) of 170 mJ is based on the test conditions that starting Tj = 150°C; L = 3 mHy, I_{SCIS} = 10.8 A, V_{CC} = 100 V during inductor charging and V_{CC} = 0 V during the time in clamp.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions		Min	Typ	Max	Unit
OFF STATE CHARACTERISTICS							
BV_{CER}	Collector to Emitter Breakdown Voltage	I_{CE} = 2 mA, V_{GE} = 0, R_{GE} = 1 kΩ, T_J = −40 to 150°C		370	400	430	V
BV_{CES}	Collector to Emitter Breakdown Voltage	I_{CE} = 10 mA, V_{GE} = 0 V, R_{GE} = 0, T_J = −40 to 150°C		390	420	450	V
BV_{ECS}	Emitter to Collector Breakdown Voltage	I_{CE} = −20 mA, V_{GE} = 0 V, T_J = 25°C		28	–	–	V
BV_{GES}	Gate to Emitter Breakdown Voltage	I_{GES} = ±2 mA		±12	±14	–	V
I_{CER}	Collector to Emitter Leakage Current	V_{CE} = 250 V, R_{GE} = 1 kΩ	T_J = 25°C	–	–	25	μA
			T_J = 150°C	–	–	1	mA
I_{ECS}	Emitter to Collector Leakage Current	V_{EC} = 24 V	T_J = 25°C	–	–	1	mA
			T_J = 150°C	–	–	40	
R_1	Series Gate Resistance			–	120	–	Ω
R_2	Gate to Emitter Resistance			10K	–	30K	Ω
ON STATE CHARACTERISTICS							
$V_{CE(SAT)}$	Collector to Emitter Saturation Voltage	I_{CE} = 6 A, V_{GE} = 4 V	T_J = 25°C	–	1.15	1.25	V
$V_{CE(SAT)}$	Collector to Emitter Saturation Voltage	I_{CE} = 10 A, V_{GE} = 4.5 V	T_J = 150°C	–	1.35	1.50	V
$V_{CE(SAT)}$	Collector to Emitter Saturation Voltage	I_{CE} = 15 A, V_{GE} = 4.5 V	T_J = 150°C	–	1.68	1.85	V
E_{SCIS}	Self Clamped Inductive Switching	L = 3.0 mHy, R_G = 1 kΩ, V_{GE} = 5 V, (Note 3)	T_J = 25°C	–	–	300	mJ
DYNAMIC CHARACTERISTICS							
$Q_{G(ON)}$	Gate Charge	I_{CE} = 10 A, V_{CE} = 12 V, V_{GE} = 5 V		–	21	–	nC
$V_{GE(TH)}$	Gate to Emitter Threshold Voltage	I_{CE} = 1 mA, V_{CE} = V_{GE}	T_J = 25°C	1.3	1.7	2.2	V
			T_J = 150°C	0.75	1.2	1.8	
V_{GEP}	Gate to Emitter Plateau Voltage	V_{CE} = 12 V, I_{CE} = 10 A		–	2.8	–	V
SWITCHING CHARACTERISTICS							
$t_{d(ON)R}$	Current Turn−On Delay Time−Resistive	V_{CE} = 14 V, R_L = 1 kΩ V_{GE} = 5 V, R_G = 1 kΩ, T_J = 25°C		–	0.9	4	μs
t_{rR}	Current Rise Time−Resistive			–	1.9	7	μs
$t_{d(OFF)L}$	Current Turn−Off Delay Time−Inductive	V_{CE} = 300 V, L = 1 mH, V_{GE} = 5 V, R_G = 1 kΩ, I_{CE} = 6.5 A, T_J = 25°C		–	4.8	15	μs
t_{fL}	Current Fall Time−Inductive			–	2.0	15	μs
THERMAL CHARACTERISTICS							
$R_{\theta JC}$	Thermal Resistance Junction to Case			–	–	1	°C/W

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Self Clamping Inductive Switching Energy (E_{SCIS25}) of 300 mJ is based on the test conditions that starting Tj = 25°C; L = 3 mHy, I_{SCIS} = 14.2 A, V_{CC} = 100 V during inductor charging and V_{CC} = 0 V during the time in clamp.

TYPICAL PERFORMANCE CURVES

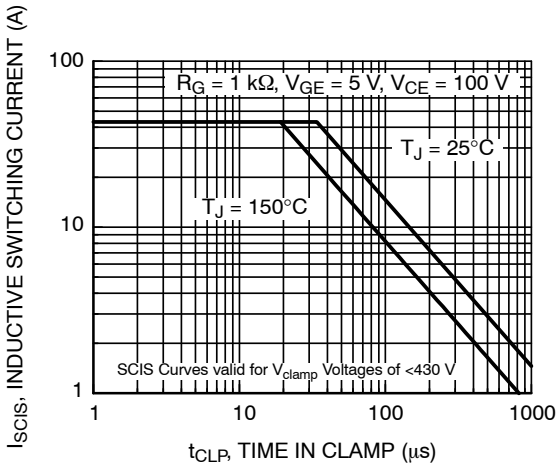


Figure 1. Self Clamped Inductive Switching Current vs. Time in Clamp

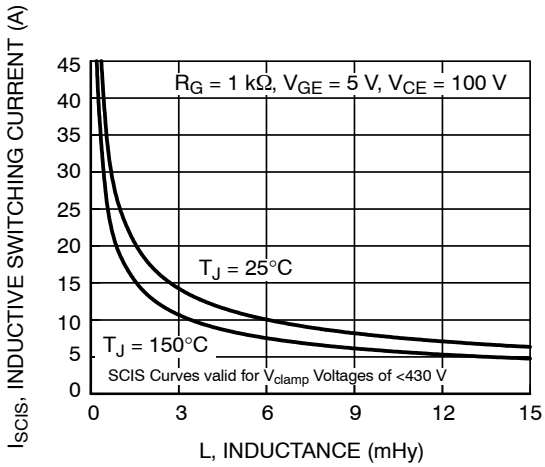


Figure 2. Self Clamped Inductive Switching Current vs. Inductance

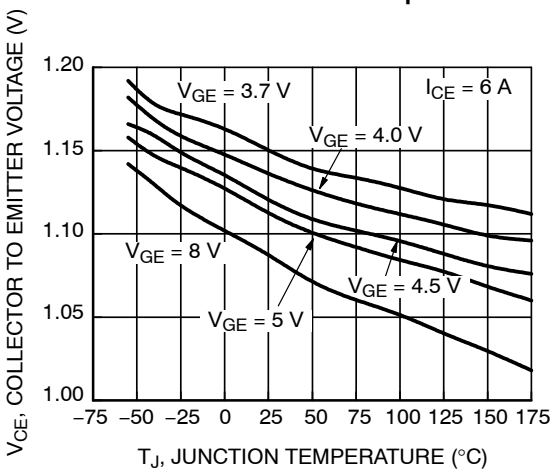


Figure 3. Collector to Emitter On−State Voltage vs. Junction Temperature

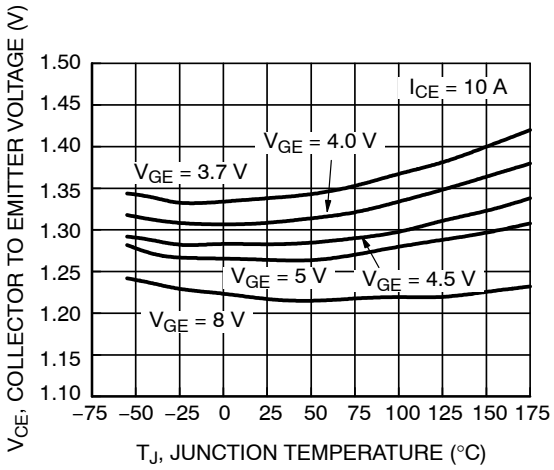


Figure 4. Collector to Emitter On−State Voltage vs. Junction Temperature

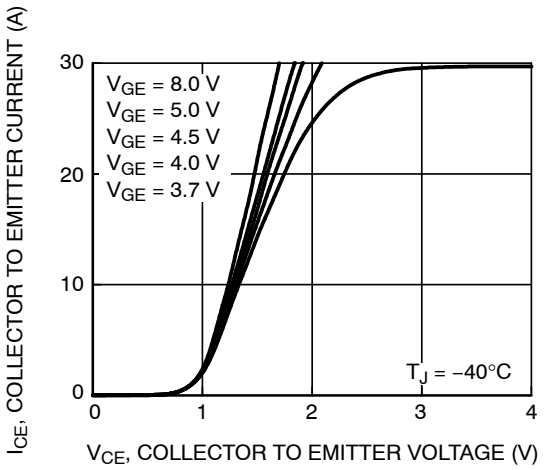


Figure 5. Collector to Emitter On−State Voltage vs. Collector Current

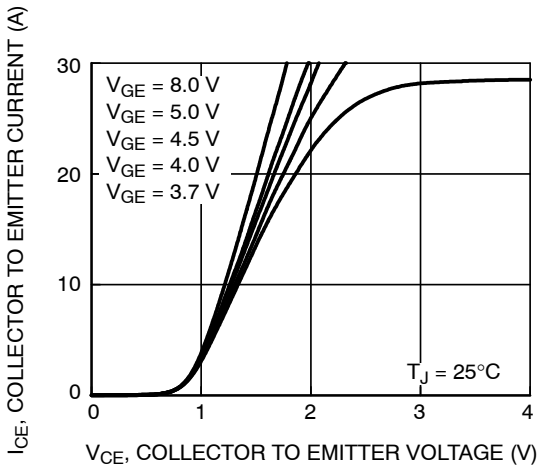


Figure 6. Collector to Emitter On−State Voltage vs. Collector Current

TYPICAL PERFORMANCE CURVES (Continued)

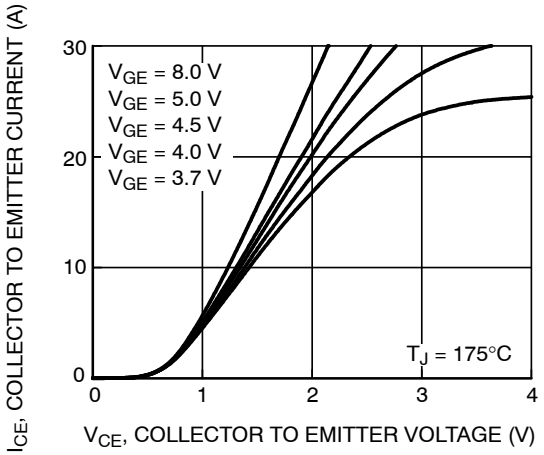


Figure 7. Collector to Emitter On−Stage Voltage vs. Collector Current

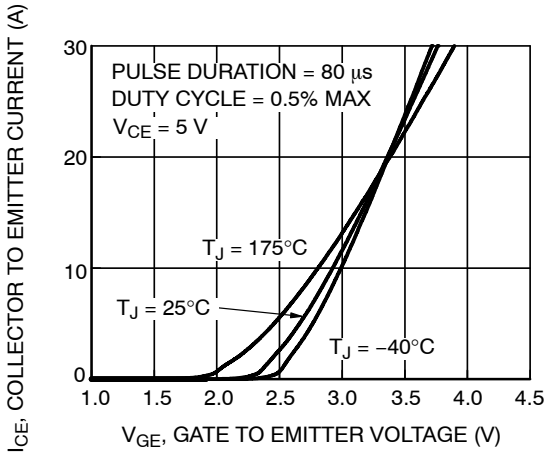


Figure 8. Transfer Characteristics

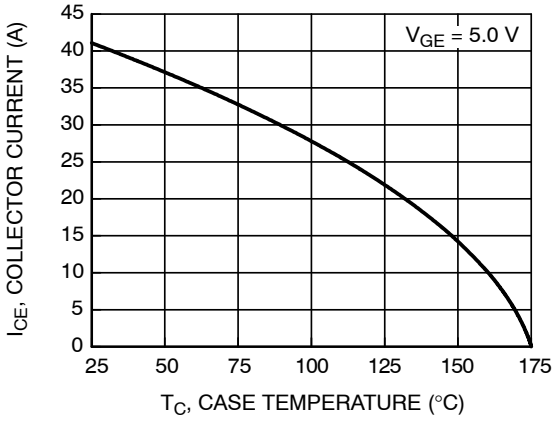


Figure 9. DC Collector Current vs. Case Temperature

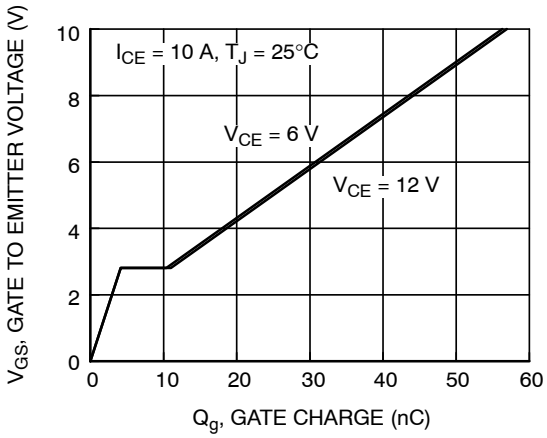


Figure 10. Gate Charge

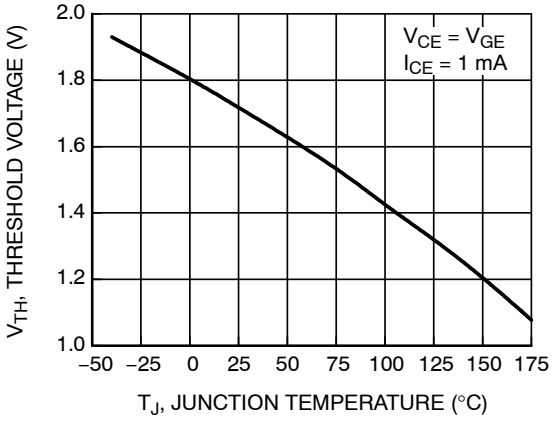


Figure 11. Threshold Voltage vs. Junction Temperature

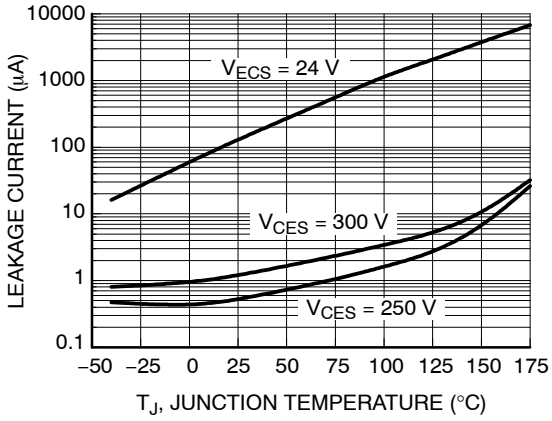


Figure 12. Leakage Current vs. Junction Temperature

TYPICAL PERFORMANCE CURVES (Continued)

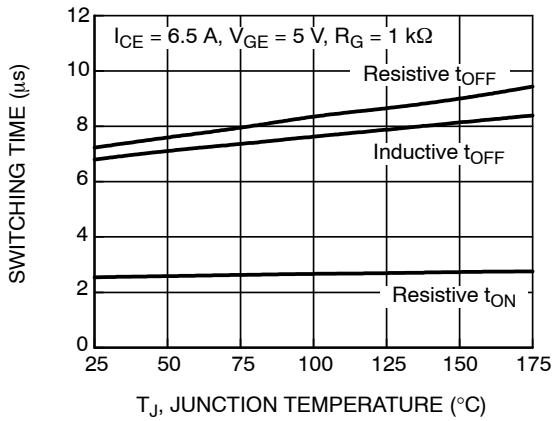


Figure 13. Switching Time vs. Junction Temperature

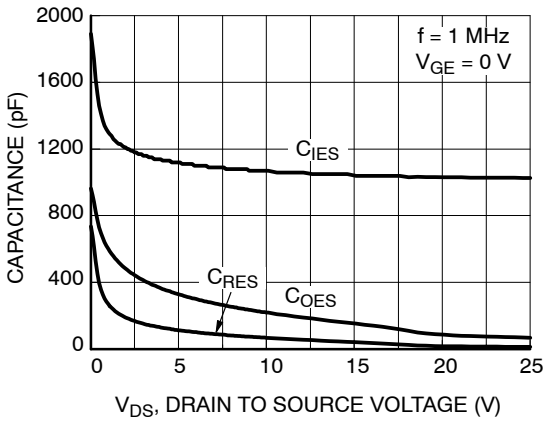


Figure 14. Capacitance vs. Collector to Emitter Voltage

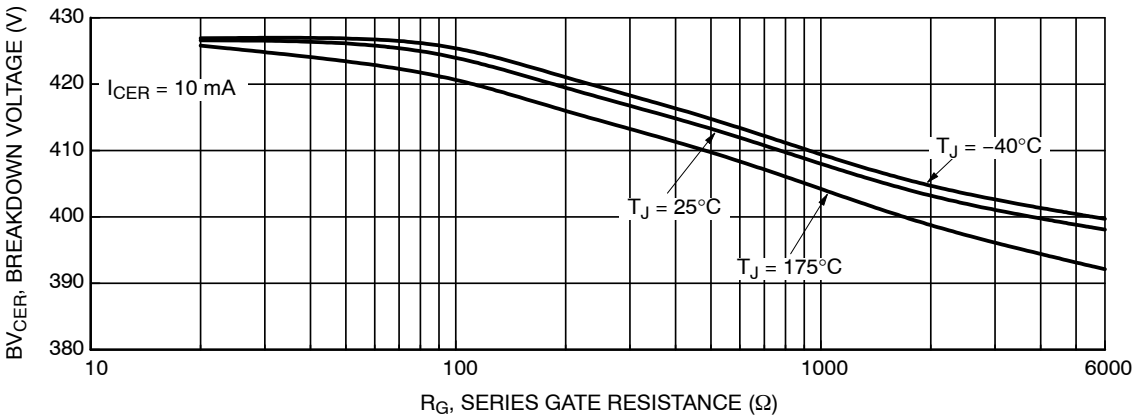


Figure 15. Breakdown Voltage vs. Series Gate Resistance

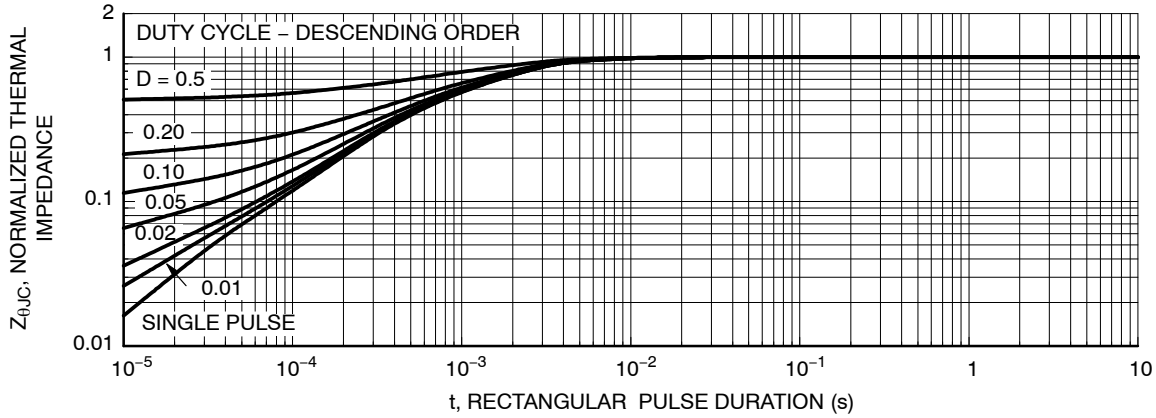


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

TYPICAL PERFORMANCE CURVES (Continued)

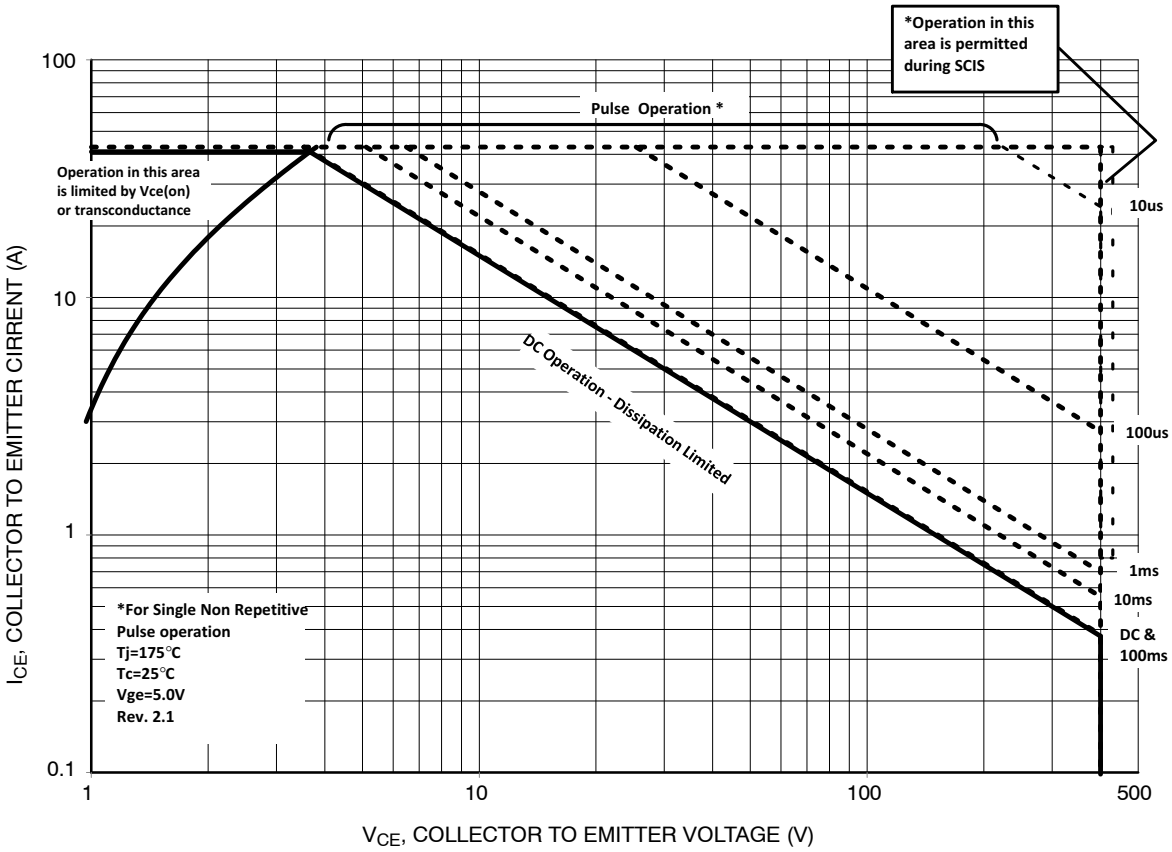


Figure 17. Forward Safe Operating Area

TEST CIRCUIT AND WAVEFORMS

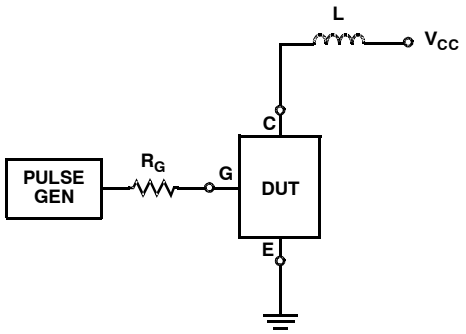


Figure 18. Inductive Switching Test Circuit

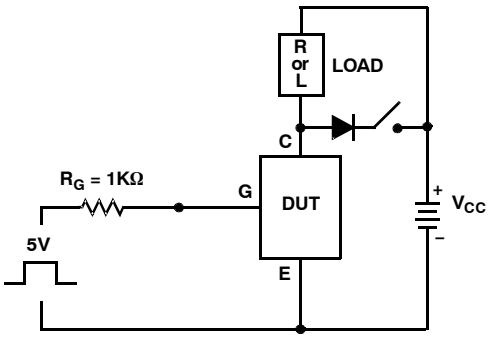


Figure 19. t_{ON} and t_{OFF} Switching Test Circuit

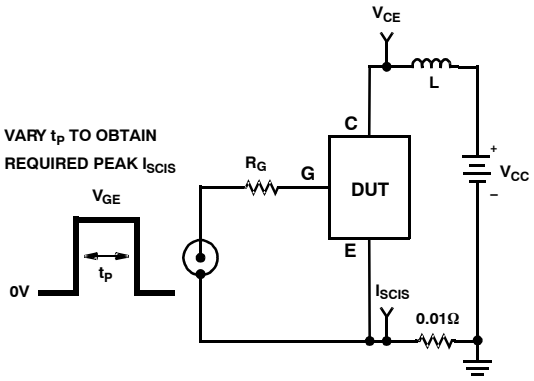


Figure 20. Energy Test Circuit

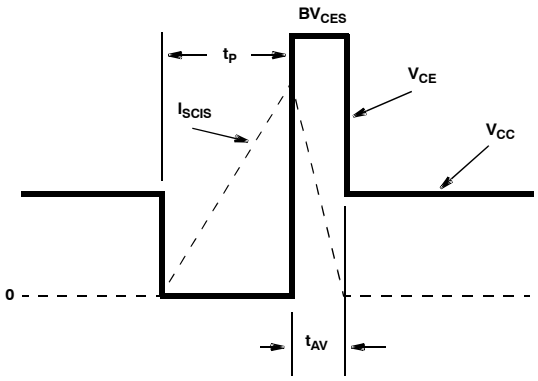
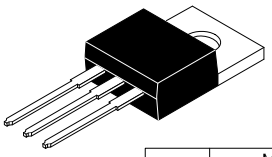


Figure 21. Energy Waveforms

PACKAGE MARKING AND ORDERING INFORMATION

Device	Device Marking	Package	Shipping†
FGB3040G2−F085	FGB3040G2	D^2PAK−3 (TO−263, 3−LEAD) (TO−263AB) (Pb−Free)	800 / Tape & Reel
FGD3040G2−F085	FGD3040G2	DPAK3 (TO−252 3 LD) (TO−252AA) (Pb−Free)	2500 / Tape & Reel
FGP3040G2−F085	FGP3040G2	TO−220−3LD (TO−220AB) (Pb−Free)	400 / Tube
FGI3040G2−F085	FGI3040G2	I2PAK (TO−262 3 LD) (TO−262AA) (Pb−Free)	400 / Tube

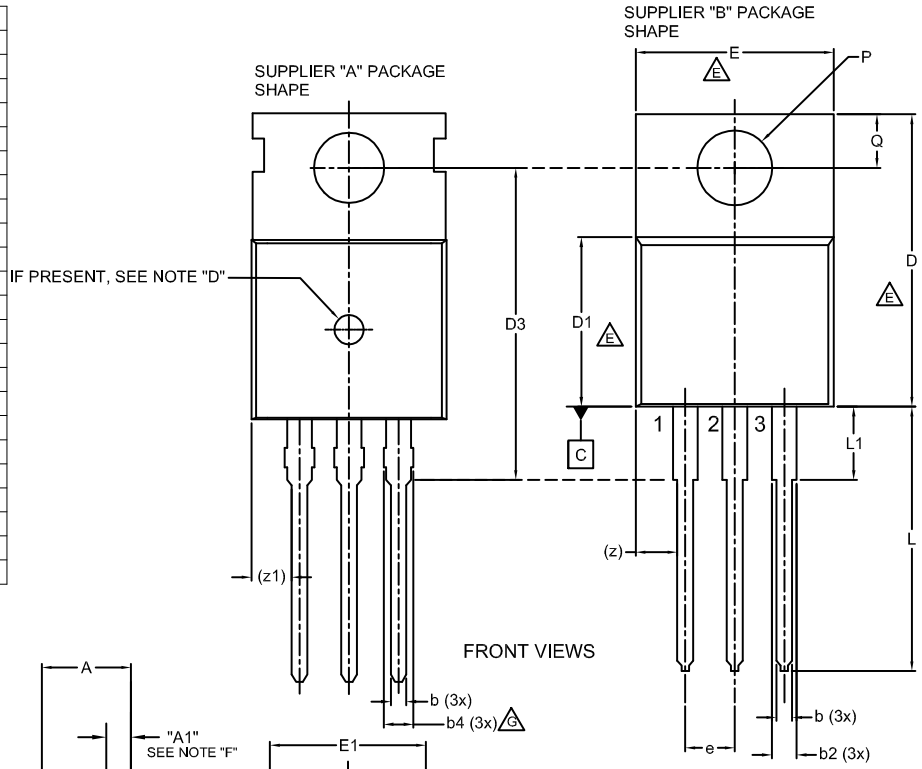
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

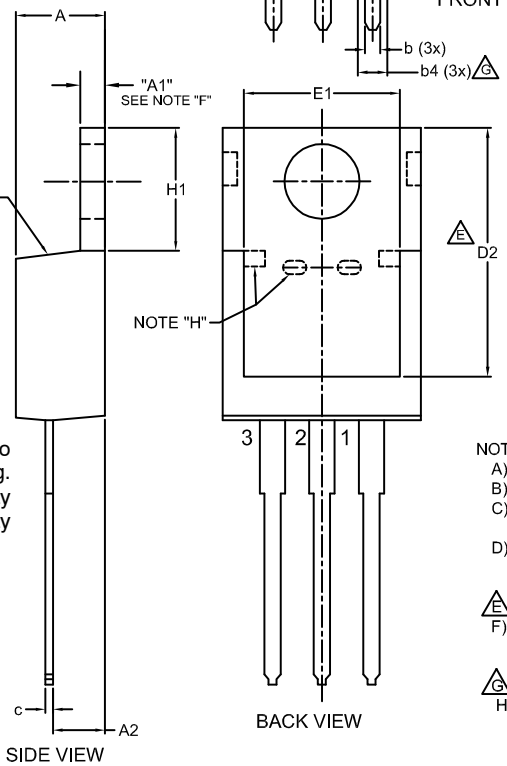


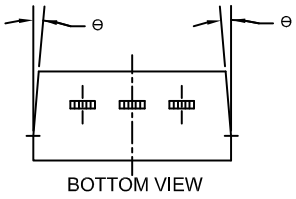
TO−220−3LD
CASE 340AT
ISSUE B

DATE 08 AUG 2022

DIM	MILLIMETERS		
	MIN.	NOM.	MAX.
A	4.00	--	4.70
A1	SEE NOTE "F"		
A2	2.10	--	2.85
b	0.55	--	1.00
b2	1.10	--	1.62
b4	1.42	--	1.62
c	0.36	--	0.60
D	13.90	--	16.30
D1	8.13	--	9.40
D2	11.50	--	14.30
D3	15.42	--	16.51
E	9.65	--	10.67
E1	7.59	--	8.65
e	2.40	--	2.67
H1	6.06	--	6.69
L	12.70	--	14.04
L1	2.70	--	4.10
P	3.50	--	4.00
Q	2.50	--	3.40
z	2.13 REF		
z1	2.06 REF		
Θ	3°	–	5°







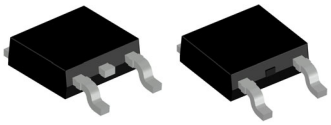
GENERIC MARKING DIAGRAM*

XXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
ZZ = Assembly Lot Code

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “▪”, may or may not be present. Some products may not follow the Generic Marking.

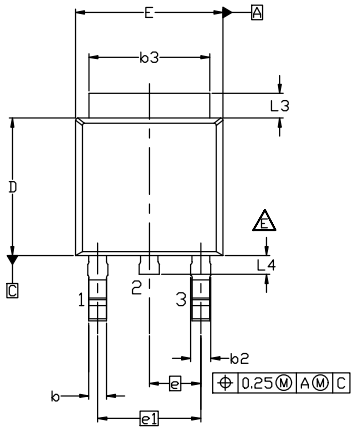
NOTES:
A) REFERENCE JEDEC, TO-220, VARIATION AB
B) ALL DIMENSIONS ARE IN MILLIMETERS.
C) DIMENSIONS COMMON TO ALL PACKAGE SUPPLIERS EXCEPT WHERE NOTED [ ].
D) LOCATION OF MOLDED FEATURE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF THE PACKAGE)
E) DOES NOT COMPLY JEDEC STANDARD VALUE.
F) "A1" DIMENSIONS AS BELOW:
SINGLE GAUGE = 0.51 - 0.61
DUAL GAUGE = 1.10 - 1.45
G) PRESENCE IS SUPPLIER DEPENDENT
H) SUPPLIER DEPENDENT MOLD LOCKING HOLES IN HEATSINK.

DOCUMENT NUMBER:	**98AON13818G**	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped “CONTROLLED COPY” in red.
DESCRIPTION:	**TO−220−3LD**	**PAGE 1 OF 1**

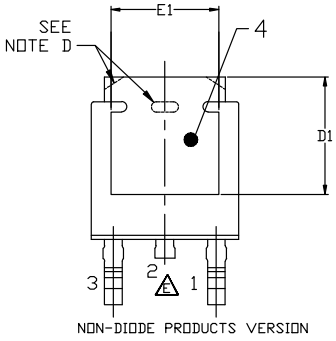


DPAK3 6.10x6.54x2.29, 4.57P
CASE 369AS
ISSUE B

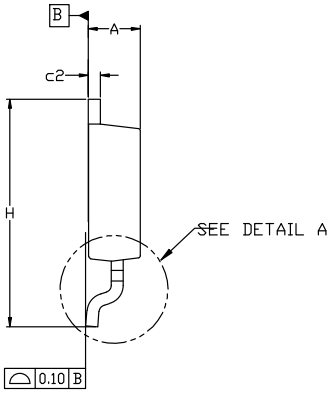
DATE 20 DEC 2023



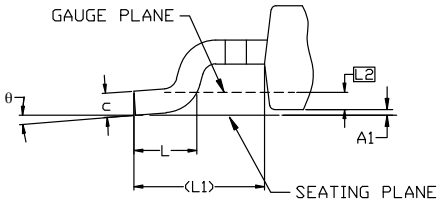
NON-DIODE PRODUCTS VERSION



NON-DIODE PRODUCTS VERSION

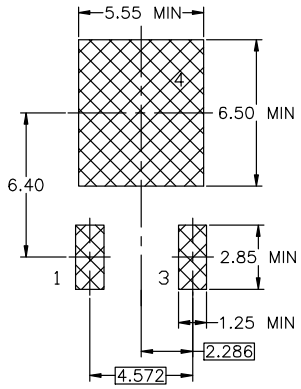


NOTES: UNLESS OTHERWISE SPECIFIED
A) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE F, VARIATION AA.
B) ALL DIMENSIONS ARE IN MILLIMETERS.
C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2018.
D) SUPPLIER DEPENDENT MOLD LOCKING HOLES OR CHAMFERED CORNERS OR EDGE PROTRUSION.
E) FOR DIODE PRODUCTS, L4 IS 0.25 MM MAX PLASTIC BODY STUB WITHOUT CENTER LEAD.
F) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR EXTRUSIONS.
G) LAND PATTERN RECOMMENDATION IS BASED ON IPC7351A STD TO228P991X239-3N.



DETAIL A
(ROTATED -90°)
SCALE: 12X

DIM	MILLIMETERS		
	MIN.	NOM.	MAX.
A	2.18	2.29	2.39
A1	0.00	–	0.127
b	0.64	0.77	0.89
b2	0.76	0.95	1.14
b3	5.21	5.34	5.46
c	0.45	0.53	0.61
c2	0.45	0.52	0.58
D	5.97	6.10	6.22
D1	5.21	---	---
E	6.35	6.54	6.73
E1	4.32	---	---
e	2.286 BSC		
e1	4.572 BSC		
H	9.40	9.91	10.41
L	1.40	1.59	1.78
L1	2.90 REF		
L2	0.51 BSC		
L3	0.89	1.08	1.27
L4	---	---	1.02
θ	0°	---	10°



LAND PATTERN RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

GENERIC MARKING DIAGRAM*

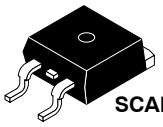
*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “▪”, may or may not be present. Some products may not follow the Generic Marking.

XXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
ZZ = Assembly Lot Code

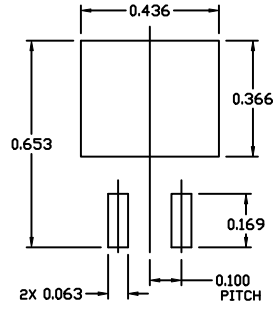
DOCUMENT NUMBER:	**98AON13810G**	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped “CONTROLLED COPY” in red.
DESCRIPTION:	**DPAK3 6.10x6.54x2.29, 4.57P**	**PAGE 1 OF 1**

D²PAK–3 (TO–263, 3–LEAD)
CASE 418AJ
ISSUE F

DATE 11 MAR 2021



SCALE 1:1



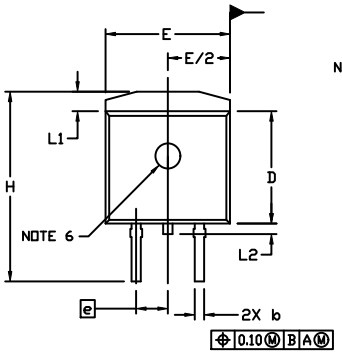
RECOMMENDED
MOUNTING FOOTPRINT

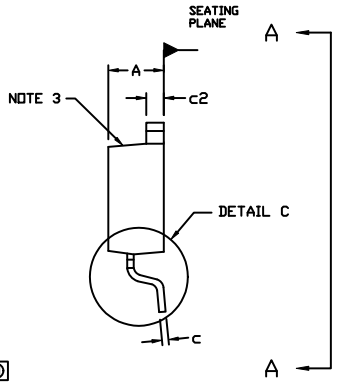
* For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

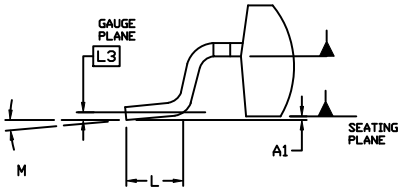
NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
2. CONTROLLING DIMENSION: INCHES
3. CHAMFER OPTIONAL.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
5. THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1, AND E1.
6. OPTIONAL MOLD FEATURE.
7. ①, ② … OPTIONAL CONSTRUCTION FEATURE CALL OUTS.

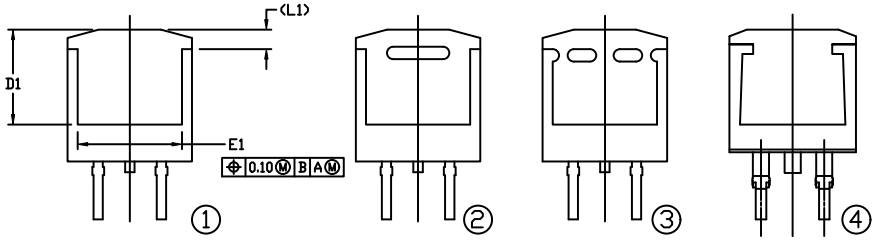
	INCHES		MILLIMETERS	
DIM	MIN.	MAX.	MIN.	MAX.
A	0.160	0.190	4.06	4.83
A1	0.000	0.010	0.00	0.25
b	0.020	0.039	0.51	0.99
c	0.012	0.029	0.30	0.74
c2	0.045	0.065	1.14	1.65
D	0.330	0.380	8.38	9.65
D1	0.260	---	6.60	---
E	0.380	0.420	9.65	10.67
E1	0.245	---	6.22	---
e	0.100 BSC		2.54 BSC	
H	0.575	0.625	14.60	15.88
L	0.070	0.110	1.78	2.79
L1	---	0.066	---	1.68
L2	---	0.070	---	1.78
L3	0.010 BSC		0.25 BSC	
M	0°	8°	0°	8°







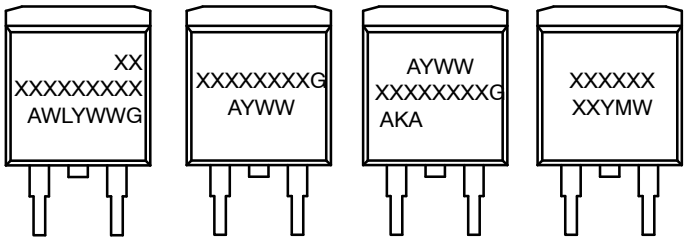
DETAIL C
TIP LEADFORM
ROTATED 90° CW



VIEW A–A

VIEW A–A
OPTIONAL CONSTRUCTIONS

GENERIC MARKING DIAGRAMS*

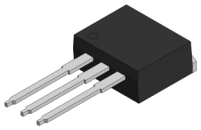


IC **Standard** **Rectifier** **SSG**

XXXXXX = Specific Device Code
A = Assembly Location
WL = Wafer Lot
Y = Year
WW = Work Week
W = Week Code (SSG)
M = Month Code (SSG)
G = Pb–Free Package
AKA = Polarity Indicator

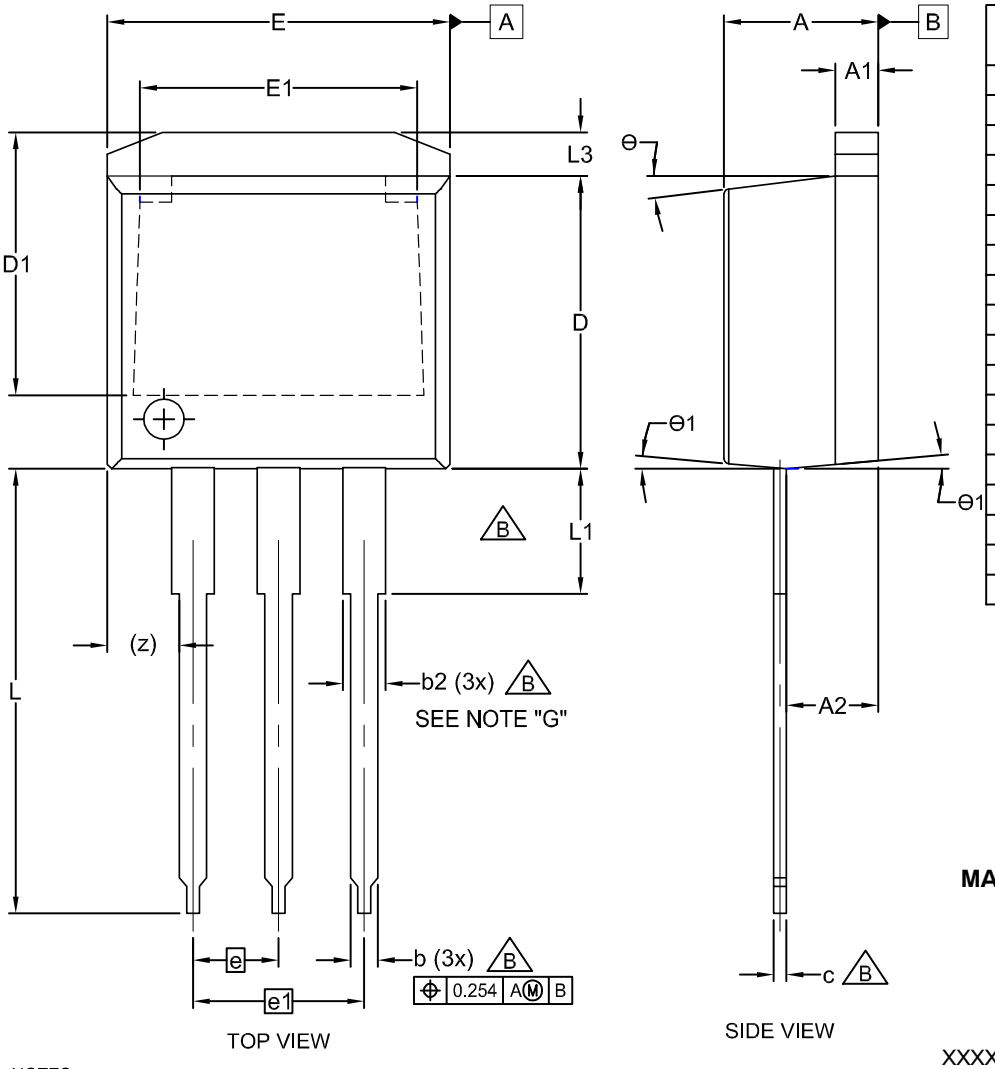
*This information is generic. Please refer to device data sheet for actual part marking. Pb–Free indicator, “G” or microdot “ ▪”, may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	**98AON56370E**	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped “CONTROLLED COPY” in red.
DESCRIPTION:	**D²PAK–3 (TO–263, 3–LEAD)**	**PAGE 1 OF 1**



I2PAK (TO−262 3 LD)
CASE 418AV
ISSUE A

DATE 30 AUG 2022

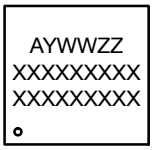


DIM	MILLIMETERS		
	MIN	NOM	MAX
A	4.06	4.45	4.83
A1	1.14	1.27	1.40
A2	2.03	2.41	2.79
b	0.64	0.77	0.90
b2	1.14	1.46	1.78
c	0.33	0.49	0.64
D	8.64	9.15	9.65
D1	6.86	7.37	7.88
E	9.65	9.97	10.29
E1	6.22	7.28	8.33
e	2.54 BSC		
e1	5.08 BSC		
L	12.70	13.72	14.73
L1	2.80	3.38	3.96
L3	1.00	1.20	1.40
z	2.13 REF		
Θ	0°	--	7°
Θ1	0°	--	5°

NOTES:

A. EXCEPT WHERE NOTED CONFORMS TO TO262 JEDEC VARIATION AA.
B. DOES NOT COMPLY JEDEC STD. VALUE.
C. ALL DIMENSIONS ARE IN MILLIMETERS.
D. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS.
E. DIMENSION AND TOLERANCE AS PER ANSI Y14.5-1994.
F. LOCATION OF PIN HOLE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF PACKAGE)
G. MAXIMUM WIDTH FOR F102 DEVICE = 1.35 MAX.

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
ZZ = Assembly Lot Code

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “▪”, may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	**98AON13814G**	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped “CONTROLLED COPY” in red.
DESCRIPTION:	**I2PAK (TO−262 3 LD)**	**PAGE 1 OF 1**

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